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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/696,759	10/29/2003	Fang-Zhong Chen	15436.247.5.1	7926
22913	7590	06/02/2006	EXAMINER	
WORKMAN NYDEGGER (F/K/A WORKMAN NYDEGGER & SEELEY) 60 EAST SOUTH TEMPLE 1000 EAGLE GATE TOWER SALT LAKE CITY, UT 84111			NGUYEN, JIMMY	
			ART UNIT	PAPER NUMBER
			2829	

DATE MAILED: 06/02/2006

Please find below and/or attached an Office communication concerning this application or proceeding.

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Office Action Summary	Application No. 10/696,759	Applicant(s) CHEN ET AL.	
	Examiner Jimmy Nguyen	Art Unit 2829	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --
Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) ☒ Responsive to communication(s) filed on 27 March 2006.
 2a) ☐ This action is **FINAL**. 2b) ☒ This action is non-final.
 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) ☒ Claim(s) 1-24 is/are pending in the application.
 4a) Of the above claim(s) _____ is/are withdrawn from consideration.
 5) ☐ Claim(s) _____ is/are allowed.
 6) ☒ Claim(s) 1-24 is/are rejected.
 7) ☐ Claim(s) _____ is/are objected to.
 8) ☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) ☐ The specification is objected to by the Examiner.
 10) ☒ The drawing(s) filed on 10/29/03 is/are: a) ☒ accepted or b) ☐ objected to by the Examiner.
 Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
 Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

- 12) ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
 a) ☐ All b) ☐ Some * c) ☐ None of:
 1. ☐ Certified copies of the priority documents have been received.
 2. ☐ Certified copies of the priority documents have been received in Application No. _____.
 3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).
 * See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

- | | |
|--|---|
| 1) <input checked="" type="checkbox"/> Notice of References Cited (PTO-892) | 4) <input type="checkbox"/> Interview Summary (PTO-413)
Paper No(s)/Mail Date. _____ |
| 2) <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948) | 5) <input type="checkbox"/> Notice of Informal Patent Application (PTO-152) |
| 3) <input type="checkbox"/> Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)
Paper No(s)/Mail Date _____ | 6) <input type="checkbox"/> Other: _____ |

DETAILED ACTION

Response to Argument

The examiner acknowledges the RCE filed 3/27/06 with the following effect;

The applicant's arguments are in mood of new ground of rejection.

Claim Rejections - 35 USC § 103

1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

2. Claims 1 - 24 are rejected under 35 U.S.C. 103(a) as being unpatentable over Beaudry et al (US 6,597,195) in view of Defelice et al (US 6,836,321).

As to claim 1, Beaudry et al disclose (figs 2, 4) a system for testing optoelectronic devices, the system comprising:

a burn-in rack (R) mountable within a support structure (IS, fig 4), said burn-in rack (R) supports a plurality of optoelectronic devices (LED) during burn-in testing and life testing (see the abstract), said burn in rack (R) with said plurality of optoelectronic devices (LED) being disposable within said support structure for life testing.

However, Beaudry et al are silent on an optical detector assembly mounted to said support structure, said detector assembly comprising a plurality of detectors, each

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of said plurality of detectors aligning with one of said plurality of optoelectronic devices to detect an output of each of said plurality of optoelectronic devices during the testing.

On the other hand, Defelice et al teach (fig 2) an optical detector assembly (122) mounted to said support structure, said detector assembly (122) comprising a plurality of detectors (120a – 120d), each of said plurality of detectors (12a – 120d) aligning with one of said plurality of optoelectronic devices (115a – 115d) to detect an output of each of said plurality of optoelectronic devices during the testing.

It would have been obvious to one having an ordinary skill in the art at the time of the invention was made to modify the teaching of Beaudry et al with plurality of detectors as taught by Defelice et al for the purpose of detecting the output signal of optoelectronic devices during the testing process.

As to claim 2, Defelice et al teach (fig 2) a system as recited in claim 1, wherein system further comprising a computer (150) in electrical communication with at least one of burn in rack and detector assembly (122).

As to claim 3, Defelice et al teach (fig 2) a system as recited in claim 2, wherein computer (150) controls life testing and burn in testing.

As to claims 4, 7, 14, Beaudry et al disclose (figs 2, 4) a system as recited in claim 1, wherein burn in rack ® comprises:

A rack base (base R) that supports a circuit board (electrical power interface connection); and

At least one diode support (C) disposed on and supported by rack base, at least one diode support (C) supporting plurality of optoelectronic devices (LED).

As to claims 5, 8, Defelice et al teach (fig 2) a system as recited in claim 1, wherein plurality of detectors (120a – 120d) are organized in an array (122).

As to claims 6, 12, 13, 20, Beaudry et al disclose (figs 2, 4) a system and a method for testing optoelectronic devices, the system and method comprising:

a burn-in rack (R) having a plurality of laser diode holders (C) and electrical signal connectors (electrical power interface connection) for electrically coupling laser diodes (LED) mounted in said holders (C) to a first electrical connector (power supply).

However, Monson et al are silent on

a test apparatus configured to hold said burn-in rack and having optical detectors arranged to receive light from said laser diodes mounted to said burn in rack and couple output signals from said optical detectors to a second electrical connector,

a computer coupled to said first and second electrical connectors, said computer creating a drive current supplied to each laser diode and measuring the light output from said optical detectors.

On the other hand, Defelice et al teach (fig 2) a test apparatus (10) configured to hold said burn-in rack and having optical detectors (120a –120d) arranged to receive

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light from said laser diodes (115a 115d) mounted to said burn in rack and couple output signals from said optical detectors (120a – 120d) to a second electrical connector,

a computer (150) coupled to said first (coupled to testing apparatus 10) and second electrical connectors (coupled to array 122), said creating a drive current supplied to each laser diode and measuring the light output from said optical detectors.

It would have been obvious to one having an ordinary skill in the art at the time of the invention was made to modify the teaching of Beaudry et al with plurality of detectors as taught by Defelice et al for the purpose of detecting the output signal of optoelectronic devices during the testing process.

As to claim 9, Beaudry et al disclose (figs 2, 4) a system of claim 6, wherein electrical connectors are edge connectors (power interface connection).

As to claim 10, Beaudry et al disclose (figs 2, 4) a system of claim 6, wherein burn in rack (R) slidably cooperates with test apparatus (IS).

As to claim 11, Beaudry et al disclose (figs 2, 4) a system of claim 6, wherein burn in rack (R) is capable of being disposed within a burn in oven (see the abstract).

As to claim 15, Beaudry et al disclose (figs 2, 4) a system of claim 6, wherein burn in rack (R) further comprises at least circuit board (electrical power interface) electrically connected to a plurality of optoelectronic device holders (C) and plurality of optoelectronic devices (LED) disposed within plurality of optoelectronic device holders (C).

As to claim 16, Defelice et al teach (fig 2) a system of claim 12, wherein means for detecting comprises a detector assembly (122) having a plurality of detectors (120a – 120d).

As to claim 17, Defelice et al teach (fig 2) a system of claim 16, wherein plurality of detectors (120a – 120d) detect electromagnetic waves propagated from plurality of optoelectronic devices (115a – 115d).

As to claims 18, 21, Defelice et al teach (fig 2) a system of claim 12 and method of claim 20, wherein means for detecting comprises a monitor detector (150) integrated within each of plurality of optoelectronic devices (240).

As to claim 19, Defelice et al teach (fig 2) a system of claim 12. wherein means for delivering comprising a computer (150) electrically connected to plurality of optoelectronic devices (240) and means for detecting.

As to claims 22 - 24, the combination of Defelice et al and Beaudry et al disclose the method further comprising step of calibrating integrated detector and optical detectors (120a 120d)) and removing burn in rack (R) and performing a burin process.

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Jimmy Nguyen whose telephone number is 571 – 272 - 1965. The examiner can normally be reached on M-F from 9 to 5.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Waynn Fammy, can be reached on 571-272-2034. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).


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JN.

April 11, 2006


VINH NGUYEN
PRIMARY EXAMINER
A.U. 2829
05/16/06